Date: 03/27/06

Sheet 1 of 2 U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET NO. APPLICATION NO. & PATENT AND TRADEMARK OFFICE 10/824,631 854163.414 MAR 2 7 2006 APPLICANT SUPPLEMENTAL Fabio Pellizzer ATION DISCLOSURE STATEMENT (Use several sheets if necessary) FILING DATE GROUP ART UNIT 2815 April 14, 2004 U.S. PATENT DOCUMENTS FILING DATE \*EXAMINER CLASS SUBCLASS DOCUMENT NUMBER DATE NAME IF APPROPRIATE INITIAL 95 5,789,277 08/04/98 Zahorik et al. 438 AA 5 438 09/29/98 Wolstenholme et al. 5,814,527 09/14/99 Reinberg et al. 257 5,952,671 AC 438 10/19/99 Wolstenholme et al. 238 5,970,336 AD 02/29/00 257 734 6,031,287 Harshfield ΑE Ziegler 50 05/29/01 438 6,238,946 ΑF 95 Maimon et al. 438 11/06/01 6,313,604 AG 04/01/03 Shukuri et al. 438 243 6,541,333 AΗ 95 09/02/03 438 6,613,604 Maimon et al. Αľ 09/09/03 438 35 Lowrey et al. 6,617,192 ΑJ 6,750,079 95 06/15/04 Lowrey et al. 438 ΑK 95 438 07/06/04 Chen 6,759,267 FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT COUNTRY DATE NUMBER YES WIPO 09/28/00 WO 00/57498 ÁΝ ΑO ΑP OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.) Palun, L. et al., "Fabrication of Single Electron Devices by Hybrid (E-Beam/DUV) AQ Lithography," Microelectronic Engineering 53, pp. 167-170, 2000. AR DATE CONSIDERED **EXAMINER** JOSEPHAGN VEN Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s)

Sheet 2 of 2

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE					ATTY, DOCKET NO.		APPLICATION NO. 10/824,631		
SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT					854163.414 APPLICANT		10/824,031		
					Fabio Pellizzer				
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U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING IF APPRO	
	ВА	6,277,705	08/17/04	Reinberg et al.		257	2		
	вв	6,943,365	09/13/05	Lowrey et al.		257	3		
	вс	6,972,430	12/06/05	Casagmade et al.		257	4		
	BD	6,969,866	11/29/05	Lowrey et al.		257	3		
	BE	2002/0070401	06/13/02	Takeuchi et al.		257	296		
	BF	2003/0075778	04/24/03	Klersy		257	536		
	ВG	2003/0219924	11/27/03	Bez et al.		438	102		
	вн	2004/0113181	01/22/04	Klebanoff et al.		134	2		
	Bì	2004/0166604	08/26/04	Ha et al.		438	102	_	
	BJ	2004/0245603	12/09/04	Lowrey et al.		257	536		
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